

Low Power And High Speed Sample And Hold For Adc Applications

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ABSTRACT

This Paper describes the improved design of low voltage sample and hold amplifier for analog to digital converter applications. The proposed design uses double sampling technique to increase the sampling rate, reliable bootstrap switch to reduce switch on resistance and to extend linear range of switch and better SFDR. The designed sample and hold operates at 100MS/s for input signal amplitude of 1.2Vpp. The circuits are designed using CSM 0.18 μ m technology incidence environment and power consumption estimated was 6.5 mwatt from 1.2V power supply.

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I. INTRODUCTION

With the explosive growth of wireless communications system and portable devices, the power reduction of integrated circuits has become a major problem. An example for low power application is a wireless communications system. With the rapid growth of internet and information demand, handheld wireless terminals are becoming increasingly popular. (i.e. UPS and handheld pad for packaged delivery.) With limited energy in a reasonable size battery, minimum power dissipation in integrated circuit is necessary. Many of the communication systems today utilized digital signal processing (DSP) to resolve the transmitted information. Therefore, an analog-to-digital interface is necessary, between the received analog signal and DSP system. This interface achieves the digitization of received waveform subject to a sampling rate requirement of the system. Being a part of communication system as mentioned above, the analog to digital interface also needs to adhere to the low power constraint.

Sample and hold (S/H) or track and hold circuits are important in signal processing circuits. They are used at the front end of analog to digital converters (ADC) and at the backend of digital to analog converters (DAC). The signal to noise ratio of an ADC is usually limited by the performance of the sample and hold block. Precision analog integrated circuits are mostly implemented by sampled data circuits in which the basic building block is sample and hold. As the supply voltage is scaling down with the technology analog sampling process becomes more challenging because of low power and for high speed application. This paper presents the design of low voltage sample and hold amplifier for ADC

applications using double sampling technique. In this paper the design and implementation of modified switch double sampling rate and low power sample and hold circuit has been described. The main application of this sample-and-hold circuit is in the low power and high speed pipelined ADCs. It has been designed in a 0.18 μ m CMOS process, which allows only a maximum supply voltage of 1.2V.

II. SAMPLE AND HOLD ARCHITECTURES

Sample and hold architectures can be divided into open loop and closed loop architectures. The main difference between the architectures is in closed loop architectures the sampling capacitor is enclosed in a feedback loop at least in hold mode.

A. Openloop Architecture

The basic open loop sample and hold architecture consists of a switch and a capacitor and is shown in figure 1(a). The operation of the circuit is explained as follows, In sample mode the switch is closed and the voltage on the capacitor tracks the input signal. In hold mode switch is opened and the input voltage level at the switch opening instant will be held by capacitor. For practical implementation input and output buffers are added to reduce hold mode feed-through and to drive load and is shown in figure 1(b). The drawbacks of the open loop architecture are accuracy limitation and signal dependent charge injection from the switch. Some of the limitations of above circuits can be overcome by using bottom plate sampling technique and is shown in figure 1(c) [1,2,4,6].

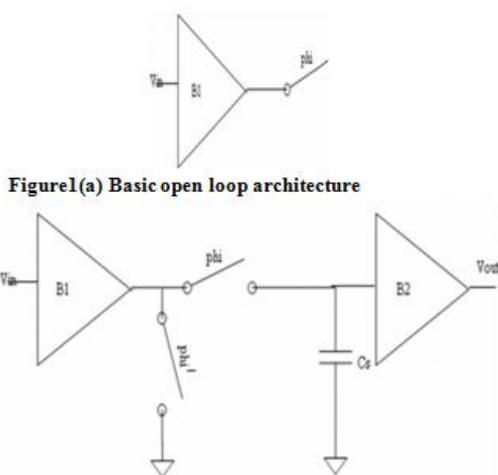


Figure1(a) Basic open loop architecture

Figure 1(b) open loop architecture with buffers

B. Closed loop architecture

Closed loop architecture a feedback loop is included between the input and output. Inclusion of feedback improves the accuracy. The basic closed loop sample and hold architecture is shown in figure. 2. In sample mode output tracks input by the feedback loop. In hold mode feedback loop is broken and capacitor holds the value of the instant at which switch is opened. The drawback of the architecture shown in figure.2 is speed limitation due to stability requirements of the circuit. Closed loop S/H architecture, commonly used in switched capacitor circuits is flip-around S/H, is shown in Fig. 3.

A simple close loop switch capacitor sample-and-hold architecture is used in this architecture Fig. 3. Here $\phi 1$ is delayed version of $\phi 3$, and $\phi 2$ is the inverse of $\phi 3$. Thus, it consists bottom-plate sampling [3] to eliminate the signal dependent clock-feed through effect and hence reduces the harmonic distortion significantly. During the sample phase ($\phi 1$), capacitor C_s is connected between signal source and op-amp's input, which is connected to the corresponding output. Thus, C_s is charged to $(V_{in} - V_{os})$, where V_{os} is the output common-mode level. In the following hold phase ($\phi 2$) C_s is disconnected to op-amp in feedback and output differential voltage becomes V_{in} , eliminating any op-amp offset voltage.

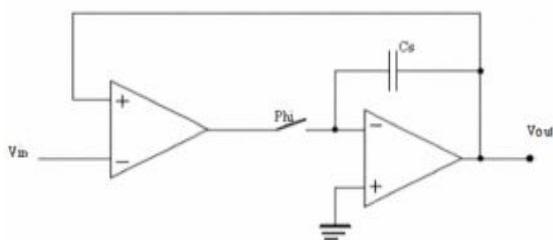


Figure 1 Closed loop sample and hold circuit

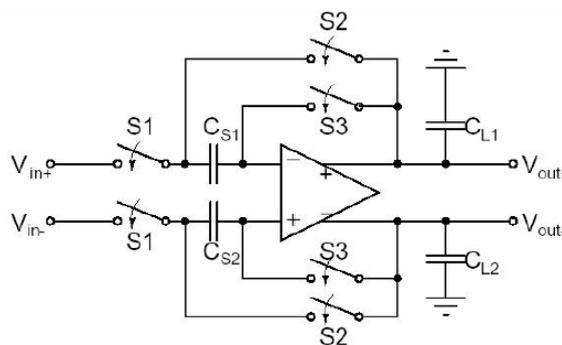


Figure 2(a): switched capacitor based sample and hold circuit

A disadvantage with the above architecture is that the output voltage varies considerably between sample and hold phases, since the differential output of op-amp is set to zero in every sample phase. So, for high-speed application the op-amp's slew-rate should be larger which increases the power dissipation considerably. Also, op-amp remains in closed loop for both phases. To solve these problems, the architecture has been modified as shown in Figure.3(b). In this architecture the op-amp remains in open-loop configuration during the sampling phase. So op-amp has not to settle down when switching from hold phase to sampling phase. Also the falling edge of switch $S1$ is delayed than $S2$ so that glitch at the differential output can be significantly reduced when switching from sampling mode to hold mode.

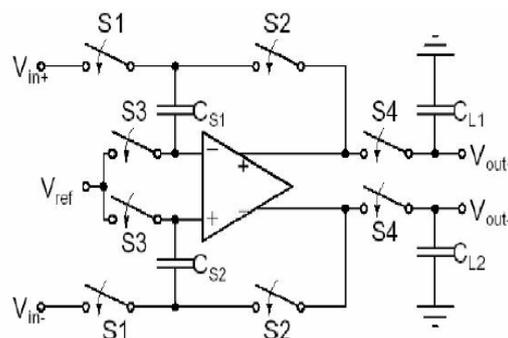


Figure 3(b) switch capacitor sample and hold circuit with modified clock

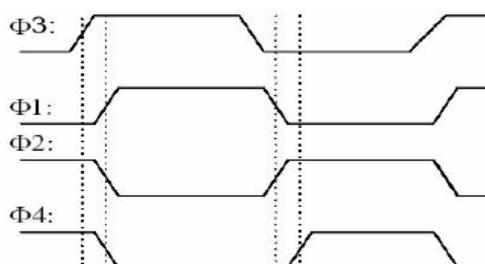


Figure .3 (c) Clock sequences

The speed of S/H block mainly depends on the time constant in the sampling and hold phase. During the sampling phase the time constant is given by,

$$\tau_S = (R_{on1} + R_{on2}) * C_S$$

Where, R_{on1} and R_{on2} are the equivalent resistances of switch S1 and S2 respectively. During the hold mode settling time constant of feedback amplifier is given by,

$$\tau_S = \frac{C_L \cdot C_{IN} + C_L \cdot C_S + C_S \cdot C_{IN}}{G_m \cdot C_H}$$

Where C_S , C_{S1} , C_{S2} , $C_L = C_{L2}$, L_2 , G_m is the transconductance of op-amp and C_m , is the op-amp's input capacitance. For 10-bit accuracy the required settling time is approximately given by $7 * \tau$.

Thus the sampling speed is limited by low value of C_s (Equation 1) and input signal bandwidth is limited by high value of C_s (Equation 2). Also the sampling noise (KT/C) depends on the size of sampling capacitor (C_s). Since this design is to be implemented in 0.18µm CMOS technology the trade-off between signal-to-noise ratio and speed is very crucial. The switch can be realized as simple MOS transistor, transmission gate or bootstrapped type. For low distortion at given power consumption the switches of transmission gate are used in this architecture. Since the maximum supply voltage is 1.8 volt the maximum swing at single end is taken as 600mV. With this output swing the minimum value of sampling capacitor (C_s) is approximately 1.1pF for signal-to-noise ratio of greater than 65dB. The maximum value of load capacitance (input of pipelined ADC) is assumed as 1.5pF.

C. Double sampling architecture

In order to utilize op-amp efficiently different techniques proposed in literature one is double sampling and other is to employ non-resetting sample and hold topology. Double sampled architecture preferable for high speed applications.

Double sampled sample and hold architecture is shown in Figure 4. In this configuration op-amp is shared by two parallel sampling circuitry operated by opposite clock phases. The operation is as follows when input is sampled by one of the sampling circuitry other circuit will be in hold operation and the reverse is going to happen when clock is complemented. The advantage of double sampling is for the same op-amp specification we can achieve twice sampling rate.

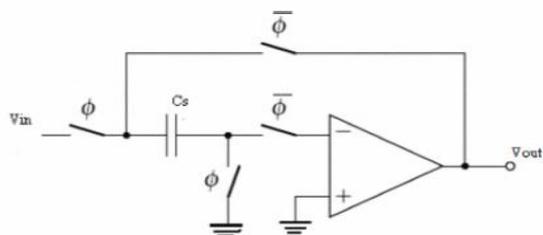


Figure 3 Double sampled sample and hold circuit

The double sampling approach introduces some unwanted phenomena in S/H circuit one is error due to finite op-amp gain and second is timing mismatch between the two signal paths and finally error due to gain mismatches in signal paths. So a careful design approach is required to overcome the above problem mentioned issues.

III. IMPLEMENTATION

The designed Sample and hold is to be used as a front-end of a 10-bit 100MHz ADC. The basic blocks for the implementation are sampling capacitor, op-amp and switch. The size of the sampling capacitor is limited by KT/C noise. In order to reduce the KT/C noise the sampling capacitor value can be found using

$$C_S > \frac{KT \cdot 12}{2^{-2N} \cdot V_{FS}^2}$$

Where N is the number of bits and V_{FS} is the Full-scale ADC voltage, for a 10-bit ADC the required sampling capacitor value to reduce KT/C noise is greater than 1.2pF. In this implementation a sampling capacitor of 1.5pF value is selected.

A. Operational amplifier

The design of fully differential op-amp is critical in the above architecture since it should meet the required specifications such as open loop gain, slew rate, unity gain frequency, common mode gain, output differential swing and input common mode range. Now for 10-bit of accuracy the gain error of op-amp should be less than +/- 1/2 LSB. If the input capacitance of op-amp is assumed to be less than 0.5pF then the value of feedback factor (D) will not be less than 0.75. This requires the open loop gain (A_0) of op-amp should be greater than 68dB which can be calculated by,

$$A_0 = \frac{2^{N+1}}{\beta}$$

Where N is the number of bits and β is the feedback factor. The architecture of op-amp can be of telescopic cascode, two-stage, regulated cascode or folded cascode type. Two stage amplifier can give higher gain and output swing but at the cost of low speed and higher power consumption. Telescopic amplifier can give high gain and speed at the cost of lower output swing. Regulated cascode can have larger power consumption. So the final choice is folded cascode amplifier, which can give larger swing than telescopic amplifier for a given open-loop gain. Also the linearity of folded cascode is better than that of other types. The topology of selected op-amp is shown in Figure 5. The gain boosters have been added to enhance the overall gain. The gain-boosters are of simple common source type so that the unity gain bandwidth of op-amp should not be affected. The common-mode feedback used is very simple and fast. The simulation results of op-amp are summarized in table 1.

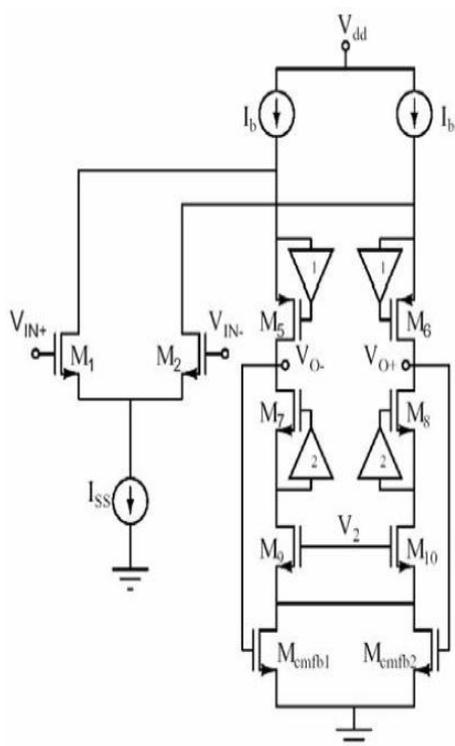


Figure 4 Schematic diagram of folded cascode

B. Switch

The switch in sample and hold can be implemented using simple NMOS transistor but it has several limitations like input dependent finite ON resistance and input dependent charge injection. In order to improve the performance of switch NMOS transistor can be replaced by a CMOS switch; proper selection of transistors aspect ratio minimizes the distortion, but this is not an effective solution. One of the commonly used techniques to solve the above problems is bootstrap switch [5]. The basic bootstrap switch implementation is shown in figure 6. Here capacitor used as a floating battery with a value V_{dd} . In holding phase sampling switch is off through switch s_5 and capacitor C_1 is charged to V_{dd} through switches s_1 and s_2 . In sampling phase this voltage value is applied between gate and source of sampling switch using switches s_1 and s_2 [5]. Although the boosted NMOS switch has good distortion characteristics; the required boost voltage is a tradeoff. In addition to the increased circuit complexity the use of the boosted voltage may cause reliability problems and increase the switching noise on the substrate. In the present sample and hold implementation a reliable bootstrap technique is selected and is shown in figure 7.

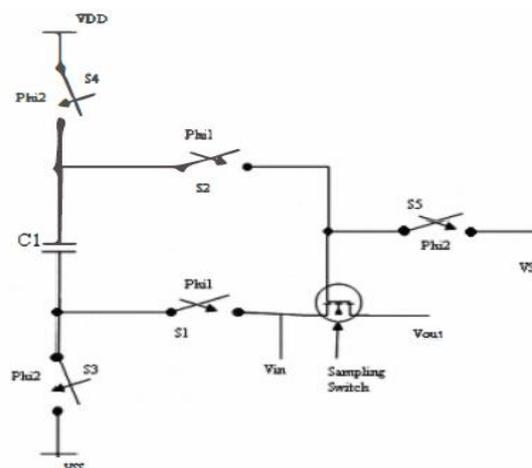


Figure 5 Basic bootstrapswitch

In the Fig .7 during S_1 phase the capacitor C_1 charges to $V_{DD}-V_{th}$. In the other phase V_{DD} is applied to the bottom plate of the capacitor. The voltage on the top plate rises to $V_{DD} - (V_{DD}-V_{th})$. This architecture gives significant area improvements and reliability is also not an issue in this given architecture because terminal voltage of any transistor does not cross the maximum supply voltage [3].

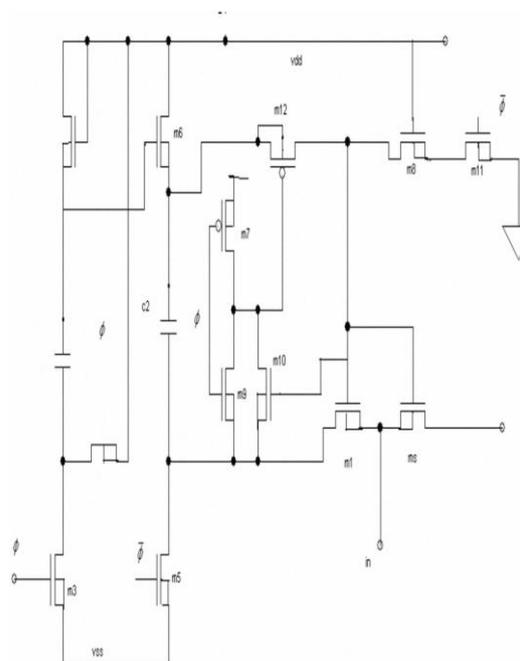


Figure 7 Reliable bootstrap switch

IV. SIMULATION RESULTS

All the circuits are designed using CSM O.18um technology in cadence environment. The designed op-amp achieves rail to rail operation and frequency response of the op-amp is shown in Figure 8 with a gain of 85db and phase margin of 54° and unity gain frequency around 450MHz. The implemented switch also achieves rail to rail operation

Figure 7 and transient simulation of switch is shown in figure 9. In order to test sample and hold circuit the method presented in [7] used. The transient simulation result of the sample and hold is shown in figure 10. Figure 11 shows the frequency spectrum for a 10 MHz input sine wave sampled at 100 MHz and the second harmonic is -60 dB. Spectrum of output signal from sample and hold circuit is shown in figure 12.

Table-1

Parameter	Hold Phase
DC Gain	78 dB
Gain bandwidth	390 MHz
Phase Margin	75 degrees
Slew Rate(Differential)	340V/ μ sec
Output swing	0.6 volt

Simulated result of OTA
 A C Response

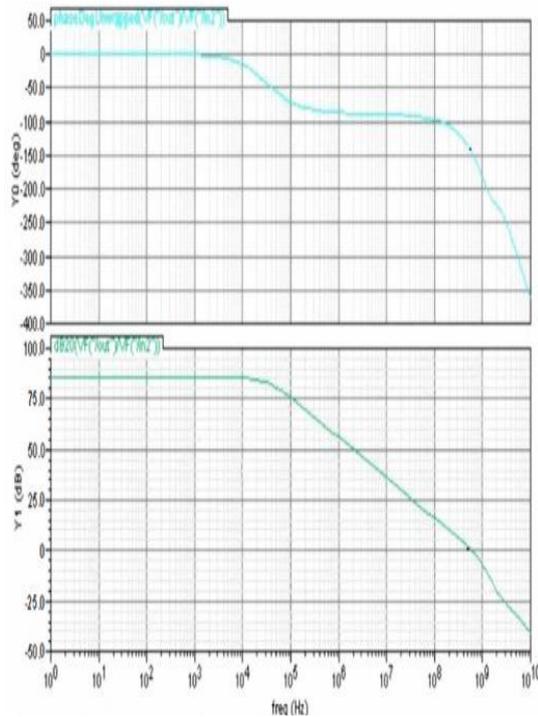


Figure 8 Operation amplifier frequency Response

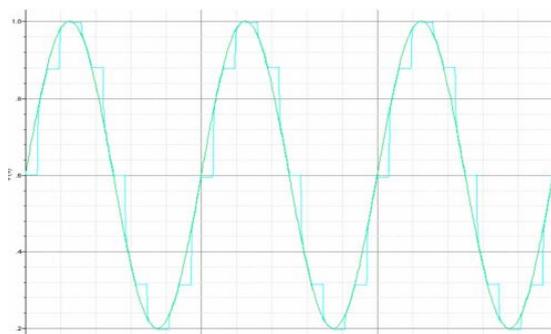


Figure 9 Transient simulation of switch at 10MHz

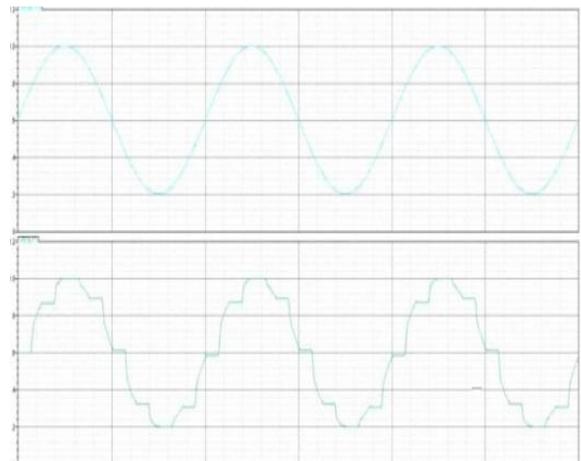


Figure 10 Transient simulation of S/H at an Input frequency 10 MHz

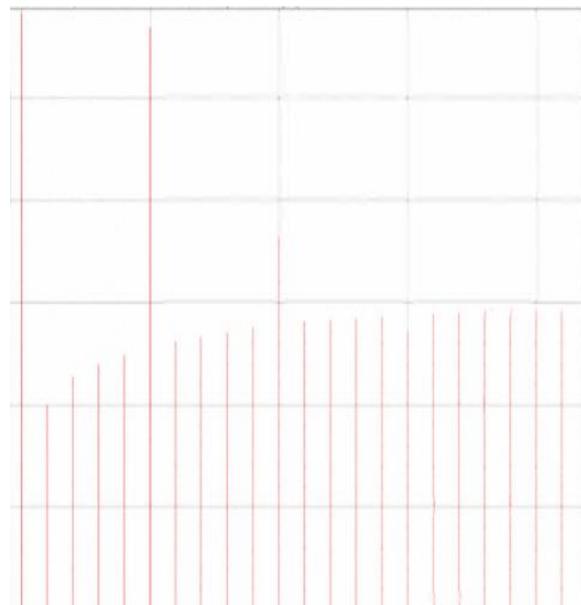


Figure 11 DFT spectrum with input frequency of input frequency and sampling frequency 100MHz

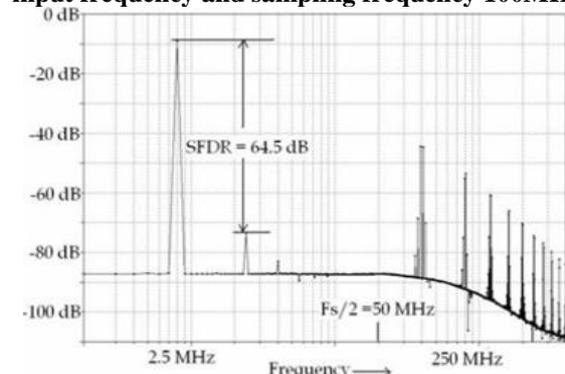


Figure 12 Spectrum of output signal from sample and hold circuit

A comparison of the designed Sample and hold with few reported articles is given in Table 2

Parameter	Ref 10	Ref 11	Ref 12	Ref 13	This work
Technology	1.2	0.25	0.35	0.5	0.18
V_{DD}	5	1.5	1.2	1.2	1.2
No of bits	10	12	NA	NA	10
Fs(MS/Sec)	50	75	50	40	100
Power(mwatt)	47	16	2.6	12	6.5
THD@fin(d B)	-67@1MHz	NA	-58@1M Hz	-50@2MH z	-60@10M Hz
SFDR(dB)	70	NA	68.5	-	64.5

REFERENCES

- [1] F. Malboerti, *Data Converters*, Springer, 2007, pp 209-240.
- [2] B. Razavi, "Design of sample and hold amplifiers for high-speed lowvoltage AID Converters," *IEEE Custom Integrated Circuits Conference*, pp.59-61, May 1997.
- [3] P.Tadeparthy and Das M., "Techniques to improve linearity of CMOS sample and-hold circuits for achieving 100 db performance at 80 MS/s", *IEEE Circuits and Systems*, pp.581-584, 2002.
- [4] P. J. Lim and B. A. Wooley, "A High-speed sample-and-hold technique using a miller hold capacitance," *IEEE Journal of Solid-state Circuits*, vol. 26, no.4 pp. 643--651, April 99 1.
- [5] J.Steensgaard, "Bootstrapped low-voltage analog switches", *IEEE Circuits and Systems*, 1999.
- [6] M.Waltari, "Circuit techniques for low voltage and high speed analog to digital converters," Ph.D thesis, Helsinki University of technology 2002.
- [7] D. A. Johns and K. Martin, *Analog Integrated Circuit Design*, John Wiley & Sons, New York, 1997.
- [8] H.Kobayashi et ai, "High speed CMOS tracklhold circuit design," *Analog integrated circuits and signal processing* ,Kluwear academic publishers, vol.27, pp. 161-170,2001.
- [9] 1.H.Huijsing and K.jandeLangen, "Compact low voltage power efficient operational amplifier cells for VLSI," *IEEE journal of Solid State circuits* Vol.33 No.10 pp.1482-1496, October 1998.
- [10] S.Brigati, F.Maloberti and G.Torelli, "A CMOS sample and hold for high speed ADC's," *IEEE Circuits and Systems*, Vol. 1, pp.163-166, January 1996.
- [11] R Lotfi, MdTaherzadeh-Sani, and O Shoaiei, "A 1.5-v 12-bit 75msamples/s fully-differential low-power sample-and-hold amplifier in 0.25-!.1m CMOS" ,*ICECS* 2003.
- [12] T.S.Lee and C.C Lu, "A 1.5V Pseudo differential Sample and Hold Circuit with Low Hold Pedastal," *IEEE Trans on Circuits and Systems-IVol. 52*, No.9, pp.1752-1757, 2005.
- [13] A Baschiroto, "A low voltage sample and hold circuit in standard CMOS technology operating at 40MS/s," *IEEE Transactions on circuits andsystem II vol.48*, no.4, pp.394-399, April 2001.
- [14] Low Power and High Speed Sample-and-Hold Circuit, Ronak Trivedi, Dhirubhai Ambani Institute of Information and Communication Technology Gandhinagar, india.
- [15] A 1.2V 80MS/S Sample and hold circuit for ADC application Y Sunil Gavaskar Reddy Department of Electronics & Communication Engineering, nurag Engineering College, Ananthagiri (Vi), Kodad, Andhrapradesh.

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